Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/075,035	LIU ET AL.	
Examiner	Art Unit	
Hien Tran	1764	

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Class	Subclass	Date	Examiner	
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55	385.3, 483	6/2/2005	нт	
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INTERFERENCE SEARCHED					
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
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